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1	14734	(three adj dimension\$2 or 3D)and(ball adj grid adj array or BGA or lead\$2 or terminals) and inspect\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 08:11
3	1	((three adj dimension\$2 or 3D)and(ball adj grid adj array or BGA or lead\$2 or terminals) and inspect\$3) and(captur\$3 or obtain\$3)near3 pluralit\$3 adj views and(front or back or side or bottom)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 08:21
4	0	((three adj dimension\$2 or 3D)and(ball adj grid adj array or BGA or lead\$2 or terminals) and inspect\$3) and(captur\$3 or obtain\$3)near3 pluralit\$3 adj views and(front or back or side or bottom)) and single near3 camera with(two adj mirrors or two adj lenses or two adj optical adj elements)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/10/28 08:22

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